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L Number	Hits	Search Text	DB	Time stamp
1	70627	(programmable with logic) pla pga fpga	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:49
2	19587	((programmable with logic) pla pga fpga) same memory	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:50
3	254	((programmable with logic) pla pga fpga) same (self near3 test)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:50
4	137	((programmable with logic) pla pga fpga) same (self near3 test) and bus	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:51
6	5	((programmable with logic) pla pga fpga) same (self near3 test) and bus) not (((programmable with logic) pla pga fpga) same (self near3 test) and bus and block)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 15:51
5	132	((programmable with logic) pla pga fpga) same (self near3 test) and bus and block	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 16:16
9	13	"773104"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/07 16:16
-	224955	programmable	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:13
-	36710	programmable near2 logic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 12:43
-	15	(programmable near2 logic) and self?repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:20

-	1967	(programmable near2 logic) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/02 18:20
-	20	(programmable with logic) and self?repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 14:22
-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 15:54
-	46175	programmable with logic	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 12:43
-	10972	(programmable with logic) and (self?repair BISR repair replace replacement spare)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 16:36

-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 16:36
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-	12	((programmable with logic) and (self?repair BISR repair replace replacement spare)) and (("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 18:44
-	10972	(programmable with logic) and (self?repair BISR repair replace replacement spare)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 16:37

-	100	("6067262" "6367042" "6651202" "6667917" "5956350" "5987632" "5920515" "6560740" "6065134" "5909404" "6300769" "6505308" "6505313" "6640321" "6691264" "6085334" "6408401" "6691252" "5577050" "5982681" "6304989" "6425103" "5764878" "5659551" "6405331" "6728910" "5748543" "6373758" "6574757" "5991907" "6003150" "5668815" "6073258" "4918378" "5006787" "5546406" "5968192" "6044481" "5404359" "5760643" "5936876" "5969538" "5994912" "6046600" "6166557" "6768694" "6154864" "6246617" "6438046" "6496947").pn. ("6202182" "6182257" "6667918" "5375091" "5675545" "5383195" "5425035" "5822228" "5471482" "6151692" "6510530" "5572712" "5805789" "5745500" "6018484" "6185138" "5355369" "6167544" "6341092" "6631086" "5570374" "5961653" "5677913" "5751729" "6108252" "6249893" "5313470" "5661732" "5668947" "5784382" "5862151" "5825785" "5963566" "6718496" "5991909" "5485467" "6292912" "5668817" "5383143" "5260950" "5570375" "5796745" "5230000" "5416783" "5416784" "5513190" "5533032" "5553082" "5612963" "5761489").pn.	USPAT	2004/08/03 16:37
-	2227	macrocell	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	4	hard adj macrocell	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/03 18:45
-	701	macrocell and test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	74	macrocell and BIST	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:51
-	60	macrocell and BIST and (repair replace replacement spare)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/04 11:52

-	0	03256461.9	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17
-	0	3256461.9	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17
-	7	"3256461"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/08/06 16:17

L Number	Hits	Search Text	DB	Time stamp
-	55977	memory with (test testing tester tested)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:22
-	22252	(memory with (test testing tester tested)).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:18
-	6371	memory with (test testing tester tested) and feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:22
-	751	memory with (test testing tester tested) and (feedback near3 path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:23
-	949	memory with (test testing tester tested) and (feedback with path)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:39
-	0	memory with (test testing tester tested) and (feedback with path) and BISR	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:32
-	104	memory with (test testing tester tested) and (feedback with path) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 13:59
-	100372	bit near3 (latch capacity storage register)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:37
-	482	(memory with (test testing tester tested) and (feedback with path)) and (bit near3 (latch capacity storage register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:37

-	50	("6667917" "6067262" "5956350" "6367042" "6651202" "5920515" "6560740" "6304989" "5987632" "5909404" "6425103" "6505308" "4918378" "5006787" "6300769" "6505313" "6640321" "6373758" "5675545" "6065134" "6249893" "5862151" "5982681" "5425035" "5577050" "5258986" "5761215" "6185709" "5748543" "6085334" "6408401" "6691252" "6718496" "5968192" "6044481" "5471482" "5936876" "6018484" "6185138" "6151692" "6167544" "6510530" "6249889" "5825785" "5668947" "5724367" "5784382" "6341092" "6388930" "5640509").pn.	USPAT	2004/05/26 12:08
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-	2	6691937.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 11:44
-	3	flare adj register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:17
-	11	flare near3 register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:36
-	37	flare with register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:19
-	3	flare with register and bisr	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:28
-	164	(scan adj (latch path chain)) with feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:43

-	1	((scan adj (latch path chain)) with feedback) and ("6667917" "6067262" "5956350" "6367042" "6651202" "5920515" "6560740" "6304989" "5987632" "5909404" "6425103" "6505308" "4918378" "5006787" "6300769" "6505313" "6640321" "6373758" "5675545" "6065134" "6249893" "5862151" "5982681" "5425035" "5577050" "5258986" "5761215" "6185709" "5748543" "6085334" "6408401" "6691252" "6718496" "5968192" "6044481" "5471482" "5936876" "6018484" "6185138" "6151692" "6167544" "6510530" "6249889" "5825785" "5668947" "5724367" "5784382" "6341092" "6388930" "5640509").pn.)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 12:25
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-	138	(scan adj (path chain)) with feedback	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 13:57
-	2	re\$load with (scan adj (path chain))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:42
-	44	memory with (test testing tester tested) and (feedback with path) and repair and scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:04
-	50	memory with (test testing tester tested) and ((feedback) same scan) and repair	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:05
-	99	re\$load with scan	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 14:42
-	2475	linear adj feedback adj shift adj register	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:29
-	15202	parallel near2 load	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 17:29
-	84	(linear adj feedback adj shift adj register) and (parallel near2 load)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:13
-	329	zerbe.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:14
-	35	zerbe.in. and jared.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:14

-	3	PURI.in. and MUKESH.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2004/05/26 19:36
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10002499_CLS
Most Frequently Occurring Classifications of Patents Returned
From A Search of 10002499 on August 03, 2004

Original Classifications

18	714/733
12	365/201
9	714/718
6	714/7
5	365/200
5	714/30
5	714/725
5	714/732
4	714/727
3	324/763
2	714/710
2	714/711
2	714/719
2	714/720
2	714/724

Cross-Reference Classifications

26	714/733
14	365/201
11	714/718
9	714/30
7	365/200
7	714/726
6	714/732
6	714/734
5	714/724
5	714/738
4	714/710
4	714/711
4	714/719
4	714/736
3	714/42
3	714/6
2	324/73.1
2	324/765
2	365/225.7
2	365/230.03
2	365/230.06
2	365/236
2	708/250
2	714/720
2	714/723
2	714/725

10002499_CLS

2 714/727
2 714/731
2 714/739
2 714/8
2 716/16

Combined Classifications

44 714/733
26 365/201
20 714/718
14 714/30
12 365/200
11 714/732
8 714/726
7 714/7
7 714/724
7 714/725
6 714/710
6 714/711
6 714/719
6 714/727
6 714/734
6 714/738
4 324/763
4 714/720
4 714/736
3 324/73.1
3 324/765
3 365/225.7
3 714/42
3 714/6
3 714/723
3 714/739
2 365/230.03
2 365/230.06
2 365/236
2 708/250
2 714/731
2 714/8
2 716/16

10002499_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10002499 on August 03, 2004

- 44 714/733 (18 OR, 26 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/733 ..Built-in testing circuit (BILBO)
- 26 365/201 (12 OR, 14 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/201 .Testing
- 20 714/718 (9 OR, 11 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/718 .Memory testing
- 14 714/30 (5 OR, 9 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
 714/1 .Reliability and availability
 714/25 ..Fault locating (i.e., diagnosis or testing)
 714/27 ...Particular access structure
 714/30Built-in hardware for diagnosing or testing
 within-system component (e.g., microprocess
 or test mode circuit, scan path)
- 12 365/200 (5 OR, 7 XR)
 Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL
 365/189.01 READ/WRITE CIRCUIT
 365/200 .Bad bit
- 11 714/732 (5 OR, 6 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing

10002499_CLSTITLES

714/732 ..Signature analysis

8 714/726 (1 OR, 7 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))

7 714/7 (6 OR, 1 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
 714/1 .Reliability and availability
 714/2 ..Fault recovery
 714/3 ...By masking or reconfiguration
 714/5Of memory or peripheral subsystem
 714/6Redundant stored data accessed (e.g.,
 duplicated data, error correction coded data,
 or other parity-type data)
 714/7Reconfiguration (e.g., adding a
 replacement storage component)

7 714/724 (2 OR, 5 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing

7 714/725 (5 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/725 ..Programmable logic array (PLA) testing

6 714/710 (2 OR, 4 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/710 .Replacement of memory spare location, portion
 or segment

10002499_CLSTITLES

6	714/711	(2 OR, 4 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/710	.Replacement of memory spare location, portion
		or segment
	714/711	..Spare row or column
6	714/719	(2 OR, 4 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/718	.Memory testing
	714/719	..Read-in with read-out and compare
6	714/727	(4 OR, 2 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/726	..Scan path testing (e.g., level sensitive sca
n		design (LSSD))
	714/727	...Boundary scan
6	714/734	(0 OR, 6 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/734	..Structural (in-circuit test)
6	714/738	(1 OR, 5 XR)
	Class 714 :	ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY
	714/699	PULSE OR DATA ERROR HANDLING
	714/724	.Digital logic testing
	714/738	..Including test pattern generator
4	324/763	(3 OR, 1 XR)
	Class 324 :	ELECTRICITY: MEASURING AND TESTING
	324/500	FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
	324/537	.Of individual circuit component or element
	324/763	..DUT including test circuit
4	714/720	(2 OR, 2 XR)

10002499 CLSTITLES

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/718 .Memory testing

714/719 ..Read-in with read-out and compare

714/720 ...Special test pattern (e.g., checkerboard,
walking ones)

4 714/736 (0 OR, 4 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/736 ..Device response compared to expected
fault-free response

3 324/73.1 (1 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/73.1 PLURAL, AUTOMATICALLY SEQUENTIAL TESTS

3 324/765 (1 OR, 2 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF
ELECTRIC COMPONENTS

324/537 .Of individual circuit component or element

324/765 ..Test of semiconductor device

3 365/225.7 (1 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/189.01 READ/WRITE CIRCUIT

365/225.7 .Having fuse element

3 714/42 (0 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/40 ...Component dependent technique

714/42Memory or storage device component fault

3 714/6 (0 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

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714/1 .Reliability and availability
 714/2 ..Fault recovery
 714/3 ...By masking or reconfiguration
 714/5Of memory or peripheral subsystem
 714/6Redundant stored data accessed (e.g.,
 duplicated data, error correction coded dat

a, or other

parity-type data)

3 714/723 (1 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/718 .Memory testing

714/723 ..Error mapping or logging

3 714/739 (1 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/738 ..Including test pattern generator

714/739 ...Random pattern generation (includes
 pseudorandom pattern)

2 365/230.03 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/230.01 ADDRESSING

365/230.03 .Plural blocks or banks

2 365/230.06 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/230.01 ADDRESSING

365/230.06 .Particular decoder or driver circuit

2 365/236 (0 OR, 2 XR)

Class 365 : STATIC INFORMATION STORAGE AND RETRIEVAL

365/230.01 ADDRESSING

365/236 .Counting

2 708/250 (0 OR, 2 XR)

Class 708 : ELECTRICAL COMPUTERS: ARITHMETIC PROCESSING
 AND CALCULATING

708/100 ELECTRICAL DIGITAL CALCULATING COMPUTER

708/200 .Particular function performed

708/250 ..Random number generation

2 714/731 (0 OR, 2 XR)

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Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive sca

n

design (LSSD))

714/731 ...Clock or synchronization

2 714/8 (0 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT
DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/2 ..Fault recovery

714/3 ...By masking or reconfiguration

714/5Of memory or peripheral subsystem

714/8Isolating failed storage location (e.g.,
sector remapping)

2 716/16 (0 OR, 2 XR)

Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
CIRCUIT OR SEMICONDUCTOR MASK

716/1 CIRCUIT DESIGN

716/12 .Routing (e.g., routing map, netlisting)

716/16 ..PLA, PLD, FPGA, OR MCM

99

PLUS Search Results for S/N 10002499, Searched August 03, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search

system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are

most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6067262	6202182
6367042	6182257
6651202	6667918
6667917	5375091
5956350	5675545
5987632	5383195
5920515	5425035
6560740	5822228
6065134	5471482
5909404	6151692
6300769	6510530
6505308	5572712
6505313	5805789
6640321	5745500
6691264	6018484
6085334	6185138
6408401	5355369
6691252	6167544
5577050	6341092
5982681	6631086
6304989	5570374
6425103	5961653
5764878	5677913
5659551	5751729
6405331	6108252
6728910	6249893
5748543	5313470
6373758	5661732
6574757	5668947
5991907	5784382
6003150	5862151
5668815	5825785
6073258	5963566
4918378	6718496
5006787	5991909

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5546406	5485467
5968192	6292912
6044481	5668817
5404359	5383143
5760643	5260950
5936876	5570375
5969538	5796745
5994912	5230000
6046600	5416783
6166557	5416784
6768694	5513190
6154864	5533032
6246617	5553082
6438046	5612963
6496947	5761489